

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Christopher Ausschnitt,	Dated: September 23, 2009
Serial Number: 10/596,614	Examiner: Young, Christopher G.
Filing date: June 19, 2006	Group Art Unit: 1795 Confirmation No.: 8458
Title: Differential Critical Dimension and Overlay Metrology Apparatus and Measurement Method	IBM Corporation D/18G, B/321, Zip 482 2070 Route 52 Hopewell Junction, NY 12533-6531

AMENDMENT UNDER 37 C.F.R. § 1.111

Hon. Commissioner for Patents
P.O. Box 1450
Alexandria VA 22313-1450

Sir:

In response to the Office Action dated June 24, 2009, Applicants respectfully request reconsideration and allowance of the above-identified application in view of the following:

Amendments to the Claims begin on page 2 of this paper.

Remarks begin on page 8 of this paper.